E·XFL



Welcome to E-XFL.COM

Understanding <u>Embedded - FPGAs (Field</u> <u>Programmable Gate Array)</u>

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Detai	ls
-------	----

Details	
Product Status	Obsolete
Number of LABs/CLBs	-
Number of Logic Elements/Cells	-
Total RAM Bits	2560
Number of I/O	202
Number of Gates	54000
Voltage - Supply	3V ~ 3.6V, 4.5V ~ 5.5V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 85°C (TA)
Package / Case	240-BFQFP
Supplier Device Package	240-PQFP (32x32)
Purchase URL	https://www.e-xfl.com/product-detail/microsemi/a42mx36-2pqg240i

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong



Power Matters."

Microsemi Corporate Headquarters One Enterprise, Aliso Viejo, CA 92656 USA Within the USA: +1 (800) 713-4113 Outside the USA: +1 (949) 380-6100 Fax: +1 (949) 215-4996 Email: sales.support@microsemi.com www.microsemi.com

© 2016 Microsemi Corporation. All rights reserved. Microsemi and the Microsemi logo are trademarks of Microsemi Corporation. All other trademarks and service marks are the property of their respective owners. Microsemi makes no warranty, representation, or guarantee regarding the information contained herein or the suitability of its products and services for any particular purpose, nor does Microsemi assume any liability whatsoever arising out of the application or use of any product or circuit. The products sold hereunder and any other products sold by Microsemi have been subject to limited testing and should not be used in conjunction with mission-critical equipment or applications. Any performance specifications are believed to be reliable but are not verified, and Buyer must conduct and complete all performance and other testing of the products, alone and together with, or installed in, any end-products. Buyer shall not rely on any data and performance specifications or parameters provided by Microsemi. It is the Buyer's responsibility to independently determine suitability of any products and to test and verify the same. The information provided by Microsemi hereunder is provided "as is, where is" and with all faults, and the entire risk associated with such information is entirely with the Buyer. Microsemi does not grant, explicitly or implicitly, to any party any patent rights, licenses, or any other IP rights, whether with regard to such information itself or anything described by such information. Information provided in this document or to any products and services at any time without notice.

About Microsemi

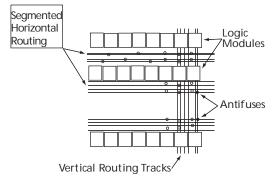
Microsemi Corporation (Nasdaq: MSCC) offers a comprehensive portfolio of semiconductor and system solutions for aerospace & defense, communications, data center and industrial markets. Products include high-performance and radiation-hardened analog mixed-signal integrated circuits, FPGAs, SoCs and ASICs; power management products; timing and synchronization devices and precise time solutions, setting the world's standard for time; voice processing devices; RF solutions; discrete components; enterprise storage and communication solutions, security technologies and scalable anti-tamper products; Ethernet solutions; Power-over-Ethernet ICs and midspans; as well as custom design capabilities and services. Microsemi is headquartered in Aliso Viejo, California, and has approximately 4,800 employees globally. Learn more at www.microsemi.com.



3.2.3.3 Antifuse Structures

An antifuse is a "normally open" structure. The use of antifuses to implement a programmable logic device results in highly testable structures as well as efficient programming algorithms. There are no pre-existing connections; temporary connections can be made using pass transistors. These temporary connections can isolate individual antifuses to be programmed and individual circuit structures to be tested, which can be done before and after programming. For instance, all metal tracks can be tested for continuity and shorts between adjacent tracks, and the functionality of all logic modules can be verified.

Figure 7 • MX Routing Structure



3.2.4 Clock Networks

The 40MX devices have one global clock distribution network (CLK). A signal can be put on the CLK network by being routed through the CLKBUF buffer.

In 42MX devices, there are two low-skew, high-fanout clock distribution networks, referred to as CLKA and CLKB. Each network has a clock module (CLKMOD) that can select the source of the clock signal from any of the following (Figure 8, page 11):

- Externally from the CLKA pad, using CLKBUF buffer
- Externally from the CLKB pad, using CLKBUF buffer
- Internally from the CLKINTA input, using CLKINT buffer
- Internally from the CLKINTB input, using CLKINT buffer

The clock modules are located in the top row of I/O modules. Clock drivers and a dedicated horizontal clock track are located in each horizontal routing channel.

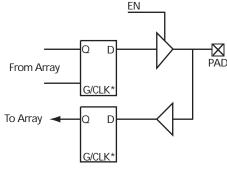
Clock input pads in both 40MX and 42MX devices can also be used as normal I/Os, bypassing the clock networks.

The A42MX36 device has four additional register control resources, called quadrant clock networks (Figure 9, page 11). Each quadrant clock provides a local, high-fanout resource to the contiguous logic modules within its quadrant of the device. Quadrant clock signals can originate from specific I/O pins or from the internal array and can be used as a secondary register clock, register clear, or output enable.



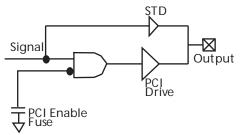
Designer software development tools provide a design library of I/O macro functions that can implement all I/O configurations supported by the MX FPGAs.

Figure 10 • 42MX I/O Module



Note: *Can be configured as a Latch or D Flip-Flop (Using C-Module)

Figure 11 • PCI Output Structure of A42MX24 and A42MX36 Devices



3.3 Other Architectural Features

The following sections cover other architectural features of 40MX and 42MX FPGAs.

3.3.1 Performance

MX devices can operate with internal clock frequencies of 250 MHz, enabling fast execution of complex logic functions. MX devices are live on power-up and do not require auxiliary configuration devices and thus are an optimal platform to integrate the functionality contained in multiple programmable logic devices. In addition, designs that previously would have required a gate array to meet performance can be integrated into an MX device with improvements in cost and time-to-market. Using timing-driven place-and-route (TDPR) tools, designers can achieve highly deterministic device performance.

3.3.2 User Security

Microsemi FuseLock provides robust security against design theft. Special security fuses are hidden in the fabric of the device and protect against unauthorized users attempting to access the programming and/or probe interfaces. It is virtually impossible to identify or bypass these fuses without damaging the device, making Microsemi antifuse FPGAs protected with the highest level of security available from both invasive and noninvasive attacks.

Special security fuses in 40MX devices include the Probe Fuse and Program Fuse. The former disables the probing circuitry while the latter prohibits further programming of all fuses, including the Probe Fuse. In 42MX devices, there is the Security Fuse which, when programmed, both disables the probing circuitry and prohibits further programming of the device.

3.3.3 Programming

Device programming is supported through the Silicon Sculptor series of programmers. Silicon Sculptor is a compact, robust, single-site and multi-site device programmer for the PC. With standalone software, Silicon Sculptor is designed to allow concurrent programming of multiple units from the same PC.



reliability. Devices should not be operated outside the recommended operating conditions.

 Table 21 •
 Recommended Operating Conditions

Parameter	Commercial	Industrial	Military	Units
Temperature Range*	0 to +70	-40 to +85	-55 to +125	°C
VCCA	4.75 to 5.25	4.5 to 5.5	4.5 to 5.5	V
VCCI	3.14 to 3.47	3.0 to 3.6	3.0 to 3.6	V

Note: *Ambient temperature (T_A) is used for commercial and industrial grades; case temperature (T_C) is used for military grades.



A sample calculation of the absolute maximum power dissipation allowed for a TQ176 package at commercial temperature and still air is given in the following equation

MaximumPowerAllowed =
$$\frac{\text{Max} \cdot \text{junction temp} \cdot (^{\circ}\text{C}) - \text{Max} \cdot \text{ambient temp} \cdot (^{\circ}\text{C})}{\theta_{ja}(^{\circ}(\text{C/W}))} = \frac{150^{\circ}\text{C} - 70^{\circ}\text{C}}{(28^{\circ}\text{C})/\text{W}} = 2.86\text{W}$$

EQ 5

The maximum power dissipation for military-grade devices is a function of θ_{jc} . A sample calculation of the absolute maximum power dissipation allowed for CQFP 208-pin package at military temperature and still air is given in the following equation

MaximumPowerAllowed =
$$\frac{\text{Max · junction temp · (°C) - Max · ambient temp · (°C)}}{\theta_{jc}(°(C/W))} = \frac{150°C - 125°C}{(6.3°C)/W} = 3.97W$$

EQ 6

Table 27 • Package Thermal Characteristics

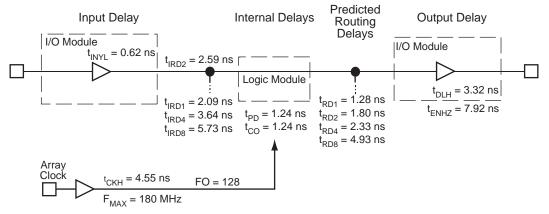
			θ_{ja}			
Plastic Packages	Pin Count	θ _{jc}	Still Air	1.0 m/s 200 ft/min.	2.5 m/s 500 ft/min.	Units
Plastic Quad Flat Pack	100	12.0	27.8	23.4	21.2	°C/W
Plastic Quad Flat Pack	144	10.0	26.2	22.8	21.1	°C/W
Plastic Quad Flat Pack	160	10.0	26.2	22.8	21.1	°C/W
Plastic Quad Flat Pack	208	8.0	26.1	22.5	20.8	°C/W
Plastic Quad Flat Pack	240	8.5	25.6	22.3	20.8	°C/W
Plastic Leaded Chip Carrier	44	16.0	20.0	24.5	22.0	°C/W
Plastic Leaded Chip Carrier	68	13.0	25.0	21.0	19.4	°C/W
Plastic Leaded Chip Carrier	84	12.0	22.5	18.9	17.6	°C/W
Thin Plastic Quad Flat Pack	176	11.0	24.7	19.9	18.0	°C/W
Very Thin Plastic Quad Flat Pack	80	12.0	38.2	31.9	29.4	°C/W
Very Thin Plastic Quad Flat Pack	100	10.0	35.3	29.4	27.1	°C/W
Plastic Ball Grid Array	272	3.0	18.3	14.9	13.9	°C/W
Ceramic Packages						
Ceramic Pin Grid Array	132	4.8	25.0	20.6	18.7	°C/W
Ceramic Quad Flat Pack	208	2.0	22.0	19.8	18.0	°C/W
Ceramic Quad Flat Pack	256	2.0	20.0	16.5	15.0	°C/W



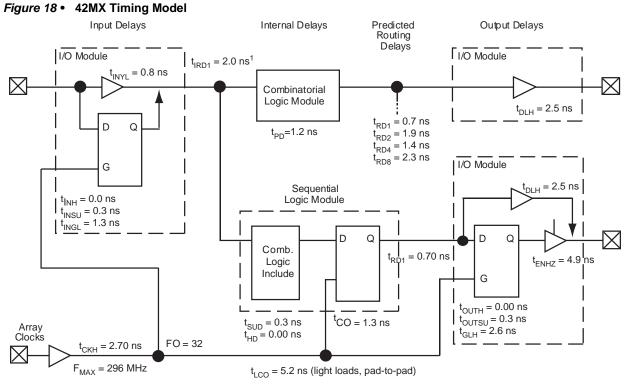
3.10 Timing Models

The following figures show various timing models.

Figure 17 • 40MX Timing Model*



Note: Values are shown for 40MX -3 speed devices at 5.0 V worst-case commercial conditions.



Note: 1. Input module predicted routing delay

Note: 2. Values are shown for A42MX09 –3 at 5.0 V worst-case commercial conditions.

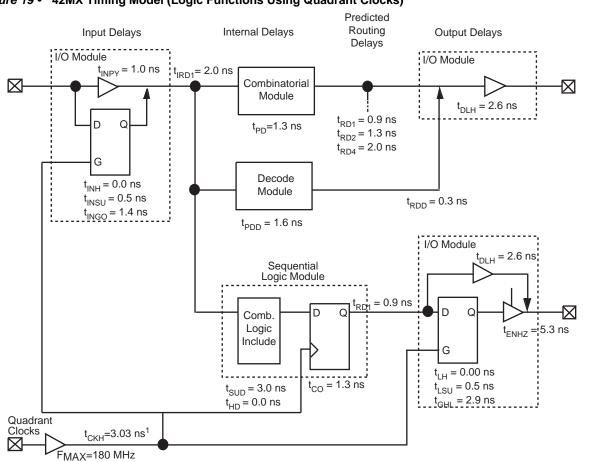
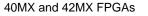


Figure 19 • 42MX Timing Model (Logic Functions Using Quadrant Clocks)

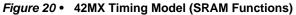
Note: 1. Load-dependent

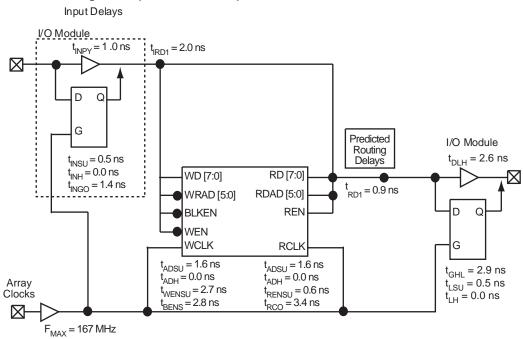
Note: 2. Values are shown for A42MX36 -3 at 5.0 V worst-case commercial conditions

Power Matters."









Note: Values are shown for A42MX36 –3 at 5.0 V worst-case commercial conditions.

3.10.1 Parameter Measurement

The following figures show parameter measurement details.

Figure 21 • Output Buffer Delays



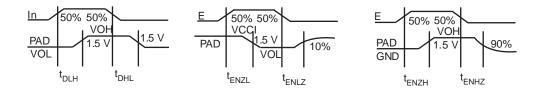
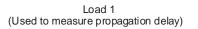




Figure 22 • AC Test Loads



To the output under test

Load 2 (Used to measure rising/falling edges)

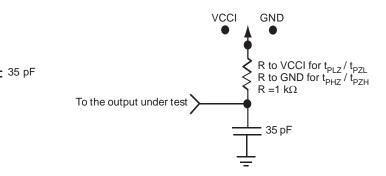
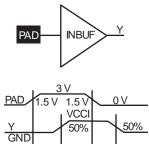
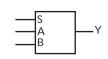


Figure 23 • Input Buffer Delays

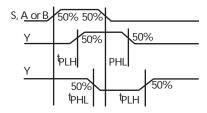


t_{INYH}

Figure 24 • Module Delays



t_{INYL}





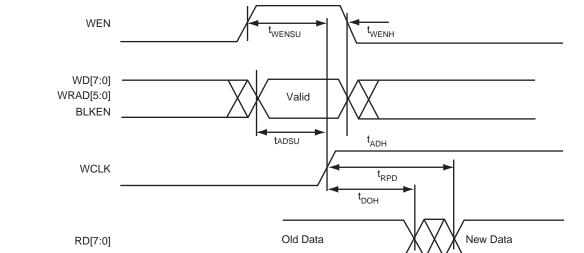


Figure 33 • 42MX SRAM Asynchronous Read Operation—Type 2 (Write Address Controlled)

3.10.7 Predictable Performance: Tight Delay Distributions

Propagation delay between logic modules depends on the resistive and capacitive loading of the routing tracks, the interconnect elements, and the module inputs being driven. Propagation delay increases as the length of routing tracks, the number of interconnect elements, or the number of inputs increases.

From a design perspective, the propagation delay can be statistically correlated or modeled by the fanout (number of loads) driven by a module. Higher fanout usually requires some paths to have longer routing tracks.

The MX FPGAs deliver a tight fanout delay distribution, which is achieved in two ways: by decreasing the delay of the interconnect elements and by decreasing the number of interconnect elements per path.

Microsemi's patented antifuse offers a very low resistive/capacitive interconnect. The antifuses, fabricated in 0.45 μ m lithography, offer nominal levels of 100 Ω resistance and 7.0 fF capacitance per antifuse.

MX fanout distribution is also tight due to the low number of antifuses required for each interconnect path. The proprietary architecture limits the number of antifuses per path to a maximum of four, with 90 percent of interconnects using only two antifuses.

3.11 Timing Characteristics

Device timing characteristics fall into three categories: family-dependent, device-dependent, and designdependent. The input and output buffer characteristics are common to all MX devices. Internal routing delays are device-dependent; actual delays are not determined until after place-and-route of the user's design is complete. Delay values may then be determined by using the Designer software utility or by performing simulation with post-layout delays.

3.11.1 Critical Nets and Typical Nets

Propagation delays are expressed only for typical nets, which are used for initial design performance evaluation. Critical net delays can then be applied to the most timing critical paths. Critical nets are determined by net property assignment in Microsemi's Designer software prior to placement and routing. Up to 6% of the nets in a design may be designated as critical.

3.11.2 Long Tracks

Some nets in the design use long tracks, which are special routing resources that span multiple rows, columns, or modules. Long tracks employ three and sometimes four antifuse connections, which increase capacitance and resistance, resulting in longer net delays for macros connected to long tracks. Typically, up to 6 percent of nets in a fully utilized device require long tracks. Long tracks add



Table 41 •A42MX16 Timing Characteristics (Nominal 3.3 V Operation) (continued) (Worst-Case Commercial
Conditions, VCCA = 3.0 V, T_J = 70°C)

			–3 Speed –2			beed	–1 S	peed	Std S	Speed	–F Speed		
Paramet	ter / Description		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
t _{PWL}	Minimum Pulse	FO = 32	5.3		5.9		6.7		7.8		11.0		ns
	Width LOW	FO = 384	6.2		6.9		7.9		9.2		12.9		ns
t _{CKSW}	Maximum Skew	FO = 32 FO = 384		0.5 2.2		0.5 2.4		0.6 2.7		0.7 3.2		1.0 4.5	ns ns
+	Input Latch External	FO = 32	0.0	2.2	0.0	2.4	0.0	2.1	0.0	5.2	0.0	4.5	
t _{SUEXT}	Set-Up	FO = 32 FO = 384	0.0		0.0		0.0		0.0		0.0		ns ns
t _{HEXT}	Input Latch External	FO = 32	3.9		4.3		4.9		5.7		8.0		ns
	Hold	FO = 384	4.5		4.9		5.6		6.6		9.2		ns
t _P	Minimum Period	FO = 32	7.0		7.8		8.4		9.7		16.2		ns
		FO = 384	7.7		8.6		9.3		10.7	400	17.8		ns
f _{MAX}	Maximum Frequency	FO = 32 FO = 384		142 129		129 117		119 108		103 94		62 56	MHz MHz
TTL Out	put Module Timing ⁵												
t _{DLH}	Data-to-Pad HIGH			3.5		3.9		4.4		5.2		7.3	ns
t _{DHL}	Data-to-Pad LOW			4.1		4.6		5.2		6.1		8.6	ns
t _{ENZH}	Enable Pad Z to HIG	4		3.8		4.2		4.8		5.6		7.8	ns
t _{ENZL}	Enable Pad Z to LOW	1		4.2		4.6		5.3		6.2		8.7	ns
t _{ENHZ}	Enable Pad HIGH to 2	<u>Z</u>		7.6		8.4		9.5		11.2		15.7	ns
t _{ENLZ}	Enable Pad LOW to 2	2		7.0		7.8		8.8		10.4		14.5	ns
t _{GLH}	G-to-Pad HIGH			4.8		5.3		6.0		7.2		10.0	ns
t _{GHL}	G-to-Pad LOW			4.8		5.3		6.0		7.2		10.0	ns
t _{LCO}	I/O Latch Clock-to-Ou (Pad-to-Pad), 64 Cloc			8.0		8.9		10.1		11.9		16.7	ns
t _{ACO}	Array Clock-to-Out (Pad-to-Pad), 64 Cloo	k Loading		11.3		12.5		14.2		16.7		23.3	ns
d _{TLH}	Capacitive Loading, L HIGH	OW to		0.04		0.04		0.05		0.06		0.08	ns/pF
d _{THL}	Capacitive Loading, H	IIGH to		0.05		0.05		0.06		0.07		0.10	ns/pF
CMOS C	Output Module Timing ⁵												
t _{DLH}	Data-to-Pad HIGH			4.5		5.0		5.6		6.6		9.3	ns
t _{DHL}	Data-to-Pad LOW			3.4		3.8		4.3		5.1		7.1	ns
t _{ENZH}	Enable Pad Z to HIG	4		3.8		4.2		4.8		5.6		7.8	ns
t _{ENZL}	Enable Pad Z to LOW	1		4.2		4.6		5.3		6.2		8.7	ns
t _{ENHZ}	Enable Pad HIGH to 2	Z		7.6		8.4		9.5		11.2		15.7	ns
t _{ENLZ}	Enable Pad LOW to 2	7		7.0		7.8		8.8		10.4		14.5	ns
t _{GLH}	G-to-Pad HIGH			7.1		7.9		8.9		10.5		14.7	ns
t _{GHL}	G-to-Pad LOW			7.1		7.9		8.9		10.5		14.7	ns
t _{LCO}	I/O Latch Clock-to-Ou (Pad-to-Pad), 64 Cloc			8.0		8.9		10.1		11.9		16.7	ns



Table 42 •A42MX24 Timing Characteristics (Nominal 5.0 V Operation) (continued) (Worst-Case Commercial
Conditions, VCCA = 4.75 V, T_J = 70°C)

		–3 S	peed	–2 Sp	beed	–1 S	peed	Std S	Speed	–F S	peed	
Parame	ter / Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
Input M	odule Propagation Delays											
t _{INPY}	Input Data Pad-to-Y		1.0		1.1		1.3		1.5		2.1	ns
t _{INGO}	Input Latch Gate-to-Output		1.3		1.4		1.6		1.9		2.6	ns
t _{INH}	Input Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{INSU}	Input Latch Set-Up	0.5		0.5		0.6		0.7		1.0		ns
t _{ILA}	Latch Active Pulse Width	4.7		5.2		5.9		6.9		9.7		ns



Table 43 •A42MX24 Timing Characteristics (Nominal 3.3 V Operation) (continued) (Worst-Case Commercial
Conditions, VCCA = 3.0 V, T_J = 70°C)

		–3 S	peed	–2 Sj	beed	–1 S	peed	Std S	peed	–F S	peed	
Paramete	er / Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
Logic Mo	odule Sequential Timing ^{3, 4}											
t _{CO}	Flip-Flop Clock-to-Output		2.1		2.0		2.3		2.7		3.7	ns
t _{GO}	Latch Gate-to-Output		3.4		1.9		2.1		2.5		3.4	ns
t _{SUD}	Flip-Flop (Latch) Set-Up Time	0.4		0.5		0.6		0.7		0.9		ns
t _{HD}	Flip-Flop (Latch) Hold Time	0.0		0.0		0.0		0.0		0.0		ns
t _{RO}	Flip-Flop (Latch) Reset-to-Output		2.0		2.2		2.5		2.9		4.1	ns
t _{SUENA}	Flip-Flop (Latch) Enable Set-Up	0.6		0.6		0.7		0.8		1.2		ns
t _{HENA}	Flip-Flop (Latch) Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{WCLKA}	Flip-Flop (Latch) Clock Active Pulse Width	4.6		5.2		5.8		6.9		9.6		ns
t _{WASYN}	Flip-Flop (Latch) Asynchronous Pulse Width	6.1		6.8		7.7		9.0		12.6		ns
Input Mo	dule Propagation Delays											
t _{INPY}	Input Data Pad-to-Y		1.4		1.6		1.8		2.2		3.0	ns
t _{INGO}	Input Latch Gate-to-Output		1.8		1.9		2.2		2.6		3.6	ns
t _{INH}	Input Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{INSU}	Input Latch Set-Up	0.7		0.7		0.8		1.0		1.4		ns
t _{ILA}	Latch Active Pulse Width	6.5		7.3		8.2		9.7		13.5		ns



Table 43 •A42MX24 Timing Characteristics (Nominal 3.3 V Operation) (continued) (Worst-Case Commercial
Conditions, VCCA = 3.0 V, T_J = 70°C)

			–3 S	peed	–2 Sp	beed	–1 Sp	beed	Std S	peed	–F S	peed	
Paramet	ter / Description		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
TTL Out	put Module Timing ⁵ (conti	nued)											
t _{LH}	I/O Latch Output Hold		0.0		0.0		0.0		0.0		0.0		ns
t _{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad) 32 I/O			7.7		8.5		9.6		11.3		15.9	ns
t _{ACO}	Array Latch Clock-to-Out (Pad-to-Pad) 32 I/O			14.8		16.5		18.7		22.0		30.8	ns
d _{TLH}	Capacitive Loading, LOV	v to HIGH		0.05		0.05		0.06		0.07		0.10	ns/pF
d _{THL}	Capacitive Loading, HIG	H to LOW		0.04		0.04		0.05		0.06		0.08	ns/pF
CMOS C	Dutput Module Timing ⁵												
t _{DLH}	Data-to-Pad HIGH			4.8		5.3		5.5		6.4		9.0	ns
t _{DHL}	Data-to-Pad LOW			3.5		3.9		4.1		4.9		6.8	ns
t _{ENZH}	Enable Pad Z to HIGH			3.6		4.0		4.5		5.3		7.4	ns
t _{ENZL}	Enable Pad Z to LOW			3.4		4.0		5.0		5.8		8.2	ns
t _{ENHZ}	Enable Pad HIGH to Z			7.2		8.0		9.0		10.7		14.9	ns
t _{ENLZ}	Enable Pad LOW to Z			6.7		7.5		8.5		9.9		13.9	ns
t _{GLH}	G-to-Pad HIGH			6.8		7.6		8.6		10.1		14.2	ns
t _{GHL}	G-to-Pad LOW			6.8		7.6		8.6		10.1		14.2	ns
t _{LSU}	I/O Latch Set-Up		0.7		0.7		0.8		1.0		1.4		ns
t _{LH}	I/O Latch Hold		0.0		0.0		0.0		0.0		0.0		ns
t _{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad) 32 I/O			7.7		8.5		9.6		11.3		15.9	ns
t _{ACO}	Array Latch Clock-to-Out (Pad-to-Pad) 32 I/O			14.8		16.5		18.7		22.0		30.8	ns
d _{TLH}	Capacitive Loading, LOV	V to HIGH		0.05		0.05		0.06		0.07		0.10	ns/pF
d _{THL}	Capacitive Loading, HIG	H to LOW		0.04		0.04		0.05		0.06		0.08	ns/pF
t _{HEXT}		O = 32 O = 486	3.9 4.6		4.3 5.2		4.9 5.8		5.7 6.9		8.1 9.6		ns ns
t _P		O = 32 O = 486	7.8 8.6		8.7 9.5		9.5 10.4		10.8 11.9		18.2 19.9		ns ns

1. For dual-module macros, use $t_{PD1} + t_{RD1} + t_{PDn}$, $t_{CO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.

2. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.

3. Data applies to macros based on the S-module. Timing parameters for sequential macros constructed from C-modules can be obtained from the Timer utility.

4. Set-up and hold timing parameters for the Input Buffer Latch are defined with respect to the PAD and the D input. External setup/hold timing parameters must account for delay from an external PAD signal to the G inputs. Delay from an external PAD signal to the G input subtracts (adds) to the internal setup (hold) time.

5. Delays based on 35 pF loading.



Table 50 • PQ 100

PQ100				
Pin Number	A40MX02 Function	A40MX04 Function	A42MX09 Function	A42MX16 Function
56	VCC	VCC	I/O	I/O
57	I/O	I/O	GND	GND
58	I/O	I/O	I/O	I/O
59	I/O	I/O	I/O	I/O
60	I/O	I/O	I/O	I/O
61	I/O	I/O	I/O	I/O
62	I/O	I/O	I/O	I/O
63	GND	GND	I/O	I/O
64	I/O	I/O	LP	LP
65	I/O	I/O	VCCA	VCCA
66	I/O	I/O	VCCI	VCCI
67	I/O	I/O	VCCA	VCCA
68	I/O	I/O	I/O	I/O
69	VCC	VCC	I/O	I/O
70	I/O	I/O	I/O	I/O
71	I/O	I/O	I/O	I/O
72	I/O	I/O	GND	GND
73	I/O	I/O	I/O	I/O
74	I/O	I/O	I/O	I/O
75	I/O	I/O	I/O	I/O
76	I/O	I/O	I/O	I/O
77	NC	NC	I/O	I/O
78	NC	NC	I/O	I/O
79	NC	NC	SDI, I/O	SDI, I/O
80	NC	I/O	I/O	I/O
81	NC	I/O	I/O	I/O
82	NC	I/O	I/O	I/O
83	I/O	I/O	I/O	I/O
84	I/O	I/O	GND	GND
85	I/O	I/O	I/O	I/O
86	GND	GND	I/O	I/O
87	GND	GND	PRA, I/O	PRA, I/O
88	I/O	I/O	I/O	I/O
89	I/O	I/O	CLKA, I/O	CLKA, I/O
90	CLK, I/O	CLK, I/O	VCCA	VCCA
91	I/O	I/O	I/O	I/O
92	MODE	MODE	CLKB, I/O	CLKB, I/O



Table 53 • PQ208

PQ208					
Pin Number	A42MX16 Function	A42MX24 Function	A42MX36 Function		
132	VCCI	VCCI	VCCI		
133	VCCA	VCCA	VCCA		
134	I/O	I/O	I/O		
135	I/O	I/O	I/O		
136	VCCA	VCCA	VCCA		
137	I/O	I/O	I/O		
138	I/O	I/O	I/O		
139	I/O	I/O	I/O		
140	I/O	I/O	I/O		
141	NC	I/O	I/O		
142	I/O	I/O	I/O		
143	I/O	I/O	I/O		
144	I/O	I/O	I/O		
145	I/O	I/O	I/O		
146	NC	I/O	I/O		
147	NC	I/O	I/O		
148	NC	I/O	I/O		
149	NC	I/O	I/O		
150	GND	GND	GND		
151	I/O	I/O	I/O		
152	I/O	I/O	I/O		
153	I/O	I/O	I/O		
154	I/O	I/O	I/O		
155	I/O	I/O	I/O		
156	I/O	I/O	I/O		
157	GND	GND	GND		
158	I/O	I/O	I/O		
159	SDI, I/O	SDI, I/O	SDI, I/O		
160	I/O	I/O	I/O		
161	I/O	WD, I/O	WD, I/O		
162	I/O	WD, I/O	WD, I/O		
163	I/O	I/O	I/O		
164	VCCI	VCCI	VCCI		
165	NC	I/O	I/O		
166	NC	I/O	I/O		
167	I/O	I/O	I/O		
168	I/O	WD, I/O	WD, I/O		



7	able	54	•	PQ240
	abic	UT		IQLIU

PQ240					
Pin Number	A42MX36 Function				
237	GND				
238	MODE				
239	VCCA				
240	GND				

Figure 46 • VQ80

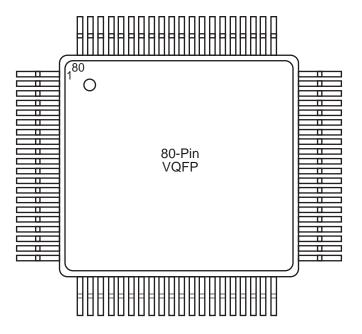


Table 55 • VQ80

VQ80			
Pin Number	A40MX02 Function	A40MX04 Function	
1	I/O	I/O	
2	NC	I/O	
3	NC	I/O	
4	NC	I/O	
5	I/O	I/O	
6	I/O	I/O	
7	GND	GND	
3	I/O	I/O	
Э	I/O	I/O	
10	I/O	I/O	
11	I/O	I/O	
12	I/O	I/O	



Figure 47 • VQ100

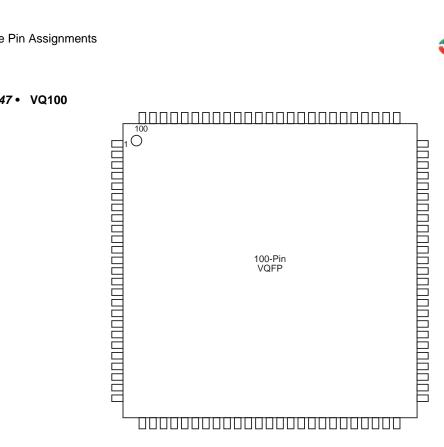


Table 56 • VQ100

VQ100		
Pin Number	A42MX09 Function	A42MX16 Function
1	I/O	I/O
2	MODE	MODE
3	I/O	I/O
4	I/O	I/O
5	I/O	I/O
6	I/O	I/O
7	GND	GND
8	I/O	I/O
9	I/O	I/O
10	I/O	I/O
11	I/O	I/O
12	I/O	I/O
13	I/O	I/O
14	VCCA	NC
15	VCCI	VCCI
16	I/O	I/O
17	I/O	I/O
18	I/O	I/O
19	I/O	I/O
20	GND	GND



Table 61 • PG132 PG132			
Pin Number	A42MX09 Function		
N10	I/O		
M10	I/O		
N11	I/O		
L10	I/O		
M11	I/O		
N12	SDO		
M12	I/O		
L11	I/O		
N13	I/O		
M13	I/O		
K11	I/O		
L12	I/O		
L13	I/O		
K13	I/O		
H10	I/O		
J12	I/O		
J13	I/O		
H11	I/O		
H12	I/O		
H13	VKS		
G13	VPP		



<i>Table 62</i> • CQ172	
138	I/O
139	I/O
140	I/O
141	GND
142	I/O
143	I/O
144	I/O
145	I/O
146	I/O
147	I/O
148	PROBA
149	I/O
150	CLKA
151	VCC
152	GND
153	I/O
154	CLKB
155	I/O
156	PROBB
157	I/O
158	I/O
159	I/O
160	I/O
161	GND
162	I/O
163	I/O
164	I/O
165	I/O
166	VCCI
167	I/O
168	I/O
169	I/O
170	I/O
171	DCLK